Application/Control No. Applicant(s)/Patent Under Reexamination TAKAHASHI, TADASHI Examiner Douglas Q. Tran Applicant(s)/Patent Under Reexamination TAKAHASHI, TADASHI Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,671,277	09-1997	Ikenoue et al.	380/7
	В	US-6,327,600	12-2001	Satoh et al.	707/530
	С	US-		,	
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			· -
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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